

Notice of References Cited

Application/Control No.

10/086,156

Applicant(s)/Patent Under
Reexamination
FEDER ET AL.

Examiner

Sandra Wegert

Art Unit

1647

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	V	Bork, P., 2000, Genome Research 10:398-400.
	W	Doerks et al., 1998, Trends in Genetics 14: 248-250.
	X	Smith et al., 1997, Nature Biotechnology 15:1222-1223.

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	V	Lehmann-Horn et al., 1999, Physiol Rev 79 (4): 1317-1372.
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